

N Channel MOSFET

Lead Free Package and Finish

Applications:

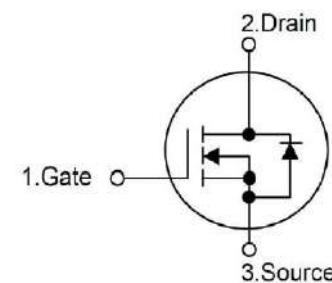
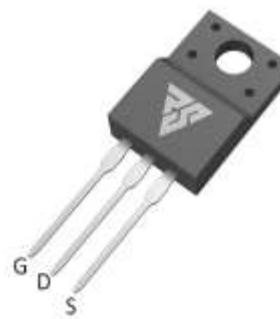
- Adapter & Charger
- SMPS Standby Power
- AC-DC Switching Power Supply
- LED driving power

Features:

- Low On Resistance
- Low Gate Charge
- Peak Current vs Pulse Width Curve
- RoHS Compliant

Ordering Information

ID	RDS(ON)(Typ.)	V _{DSS}
20A	0.39Ω	650V



Not to Scale

Part Number	Package	Marking
RS20N65F	TO-220F	RS20N65F

Absolute Maximum Ratings T_c=25°C unless otherwise specified

Symbol	Parameter	RS20N65F	Units
V _{DSS}	Drain-to-Source Voltage (Note*1)	650	V
I _D	Continuous Drain Current	20	A
I _{D@ 100 °C}	Continuous Drain Current	12	
I _{DM}	Pulsed Drain Current (Note*2)	80	
P _D	Power Dissipation	90	W
	Derating Factor above 25°C	0.74	W/°C
V _{GS}	Gate-to-Source Voltage	±30	V
E _A S	Single Pulse Avalanche Energy L=10mH V _{DD} =50V R _G =25Ω T _J =25°C	640	mJ
T _L TPKG	Maximum Temperature for Soldering		°C
	Leads at 0.063in(1.6mm)from Case for 10 seconds	300	
	Package Body for 10 seconds	260	
T _J and T _{TSG}	Operating Junction and Storage Temperature Range	-55 to 150	

*Drain Current Limited by Maximum Junction Temperature

Caution:Stresses greater than those listed in the "Absolute Maximum Ratings" Table may cause permanent damage to the device.

Thermal Resistance

Symbol	Parameter	RS20N65F	Units	Test Conditions
R _{θJC}	Junction-to-Case	1.42	°C/W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of +150°C.
R _{θJA}	Junction-to-Ambient	62.5		1 cubic foot chamber, free air.

OFF Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain-to-source Breakdown Voltage	650	--	--	V	VGS=0V, ID=250μA
IDSS	Drain-to-Source Leakage Current	--	--	1.0	μA	VDS=650V, VGS=0V
IGSS	Gate-to-Source Forward Leakage	--	--	100	nA	VGS=+30V VDS=0V
	Gate-to-Source Reverse Leakage	--	--	-100		VGS=-30V VDS=0V

ON Characteristics TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain-to-Source On-Resistance	--	0.39	0.47	Ω	VGS=10V, ID=10A
VGS(TH)	Gate Threshold Voltage	2.0	--	4.0	V	VGS=VDS, ID=250μA
gfs	Forward Trans conductance		--	9.7	S	VDS=15V, ID=8A

Resistive Switching Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn-on Delay Time	--	31	--	nS	VDS=325V ID=20A RG=25Ω (Note:3,4)
trise	Rise Time	--	25	--		
td(OFF)	Turn-OFF Delay Time	--	93	--		
tfall	Fall Time	--	25	--		

Dynamic Characteristics Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	2810	--	pF	VGS=0V VDS=25V f=1.0MHz
Coss	Output Capacitance	--	235	--		
Crss	Reverse Transfer Capacitance	--	8.9	--		
Qg	Total Gate Charge	--	50.2	--	nC	VDS=520V ID=20A VGS=10V (Note:3,4)
Qgs	Gate-to-Source Charge	--	1634	--		
Qgd	Gate-to-Drain("Miller") Charge	--	17.5	--		

Source-Drain Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I _s	Continuous Source Current	--	--	20	A	Integral pn-diode in MOSFET
I _{SM}	Maximum Pulsed Current	--	--	80	A	
V _{SD}	Diode Forward Voltage	--	--	1	V	I _s =20A, V _{GS} =0V V _{GS} =0V I _s =20A, dI/dt=100A/μs
t _{rr}	Reverse Recovery Time	--	486	--	nS	
Q _{rr}	Reverse Recovery Charge	--	5.5	--	μC	

Notes:

- *1.T_J=±25°C to +150°C.
- *2.Repetitive rating;pulse width limited by maximum junction temperature.
- *3.Pulse width≤300μs;duty cycle ≤1%.
- *4.Basically not affected by temperature.

Typical Feature curve

Figure1.Typical Output Characteristics

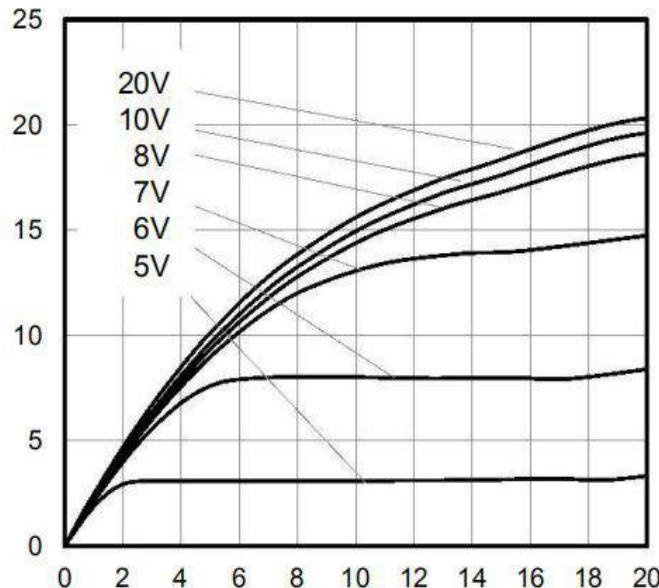


Figure2.Typical Transfer Characteristics

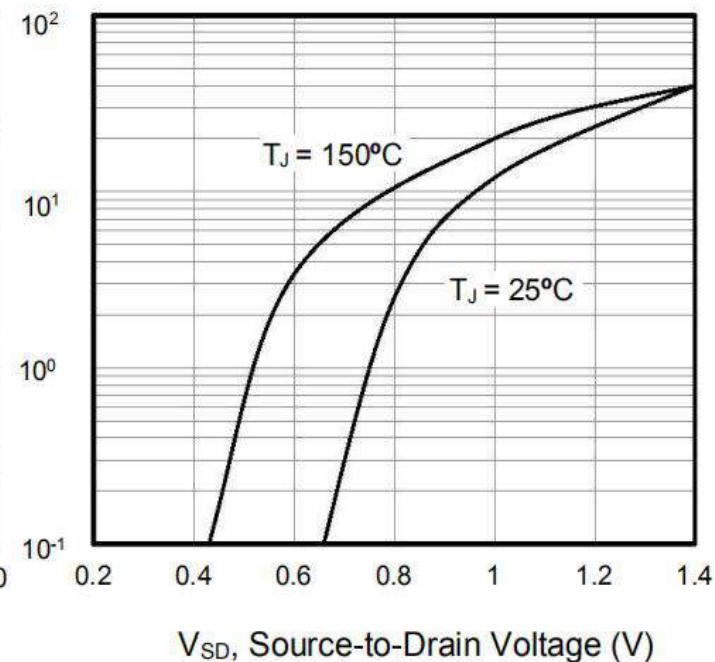


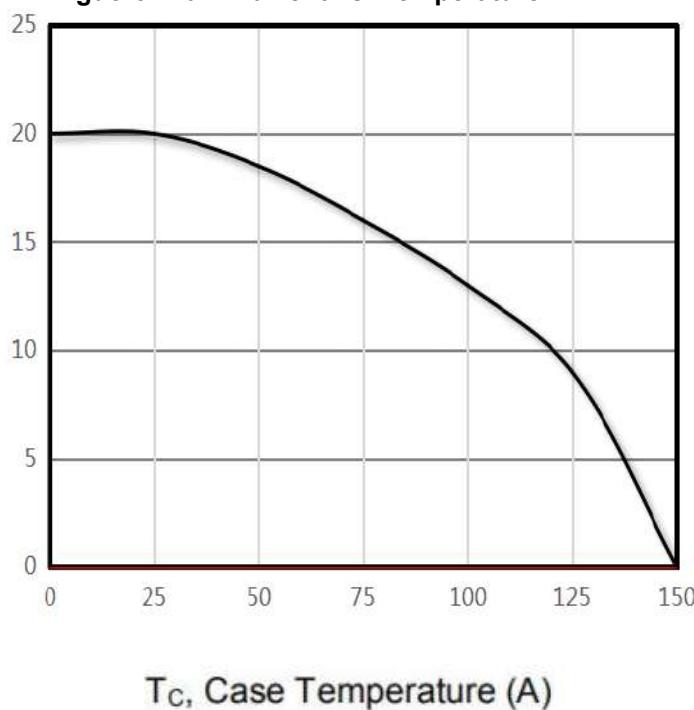
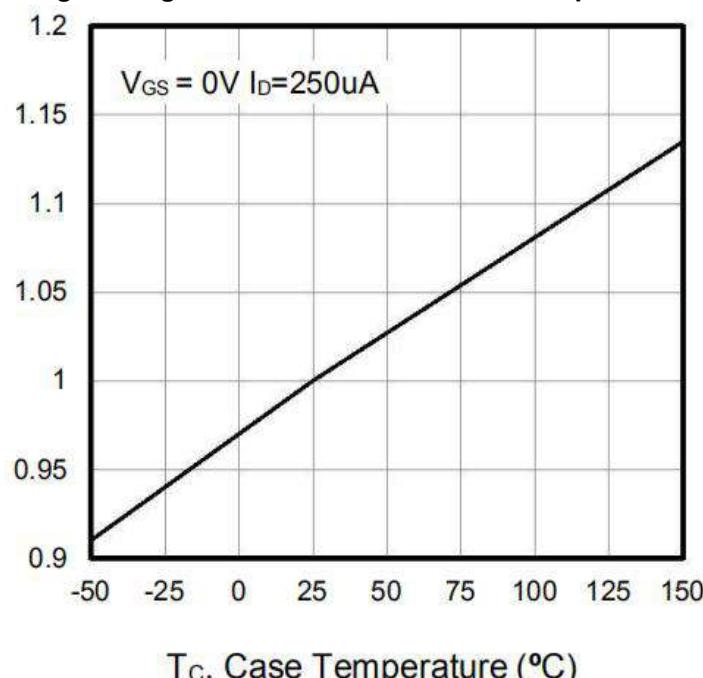
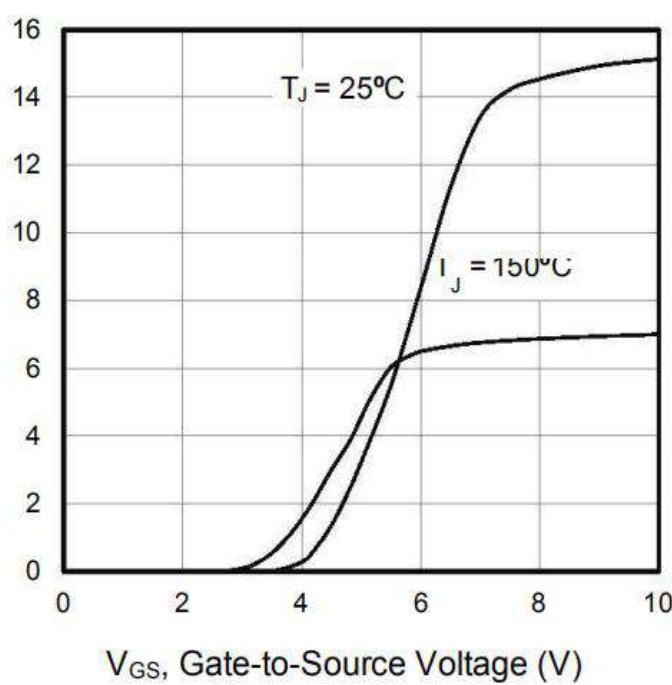
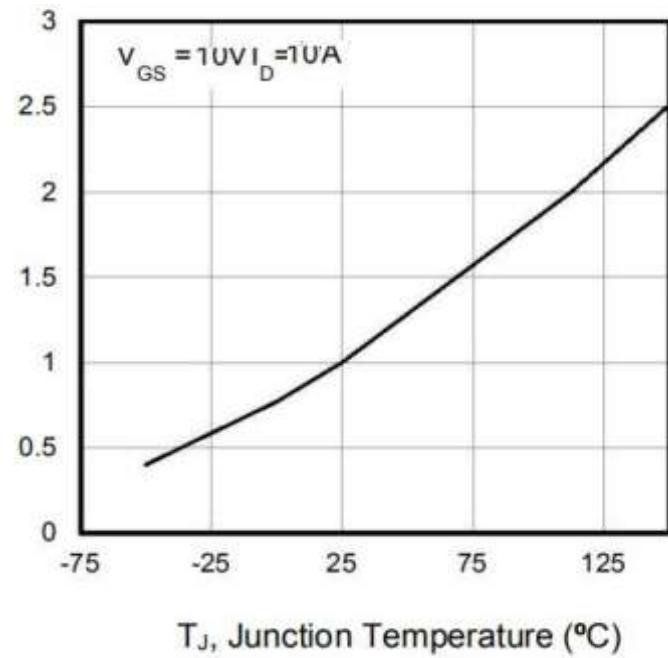
Figure3.Drain Current vs. Temperature**Figure4. BVDSS Variation vs. Temperature****T_c, Case Temperature (A)****T_c, Case Temperature (°C)****Figure5.Transfer Characteristics****Figure 6. On-Resistance vs. Temperature****V_{GS}, Gate-to-Source Voltage (V)****T_j, Junction Temperature (°C)**

Figure 7. Capacitance

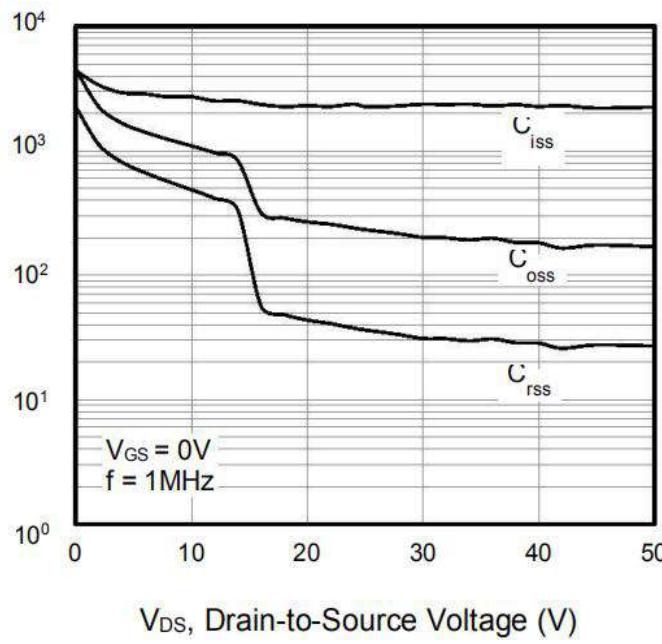
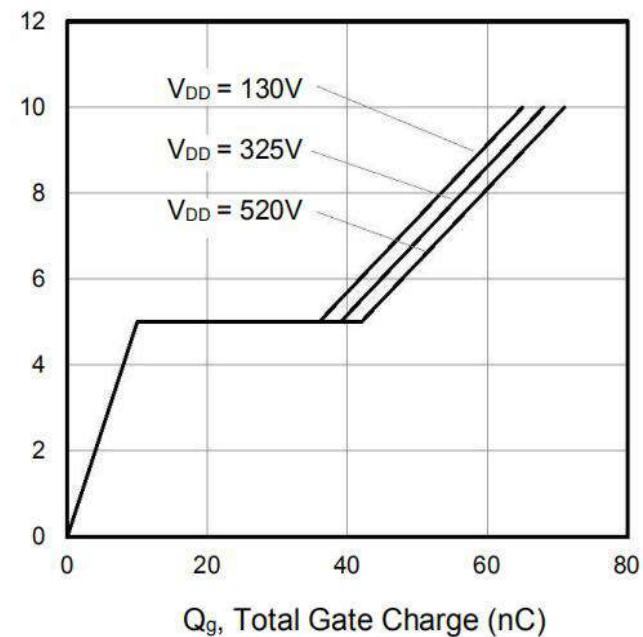


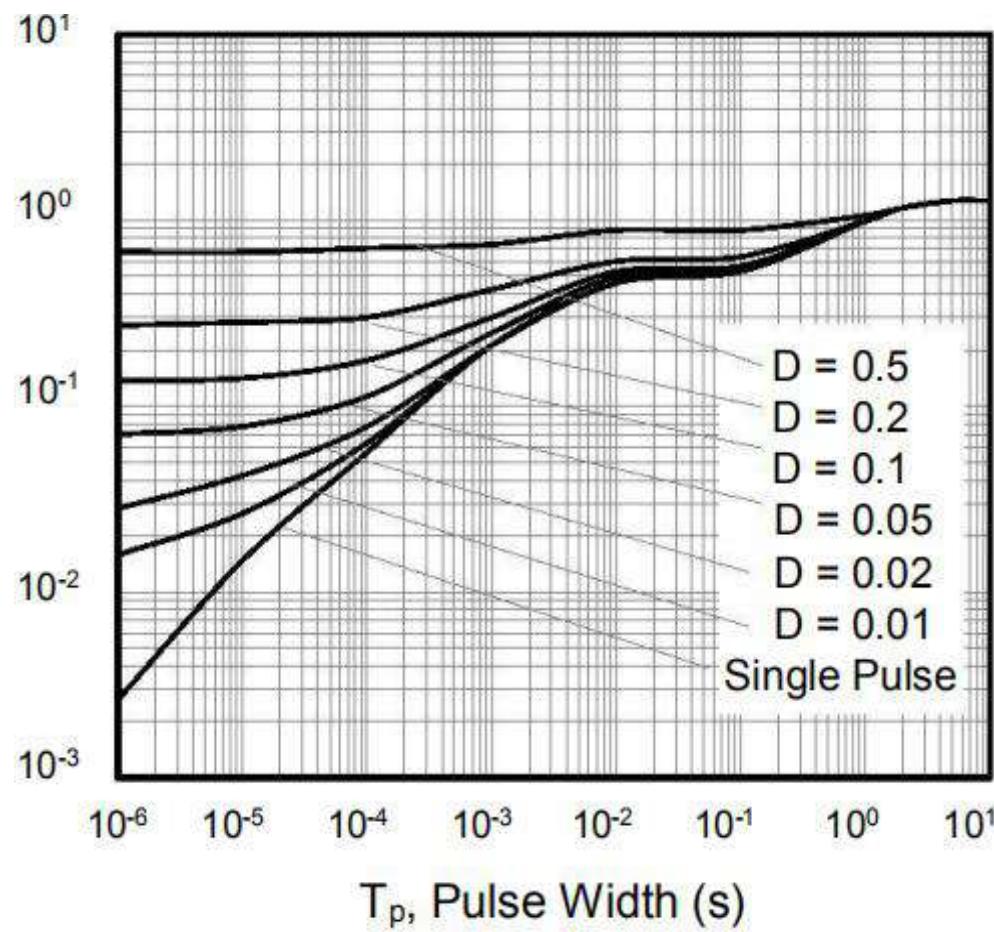
Figure 8. Gate Charge



V_{DS} , Drain-to-Source Voltage (V)

Q_g , Total Gate Charge (nC)

Figure9. Transient Thermal Impedance



Test Circuits and Waveforms

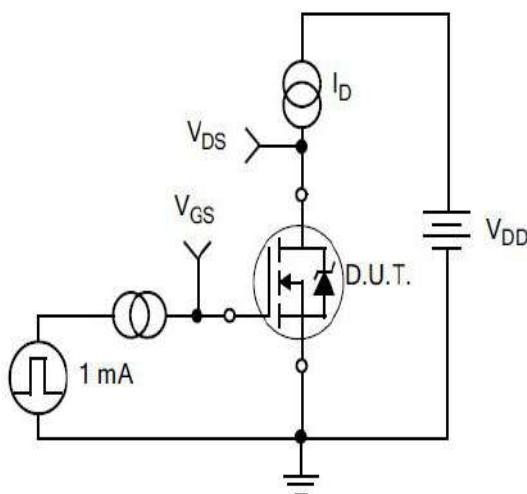


Figure11.
Gate Charge Test Circuit

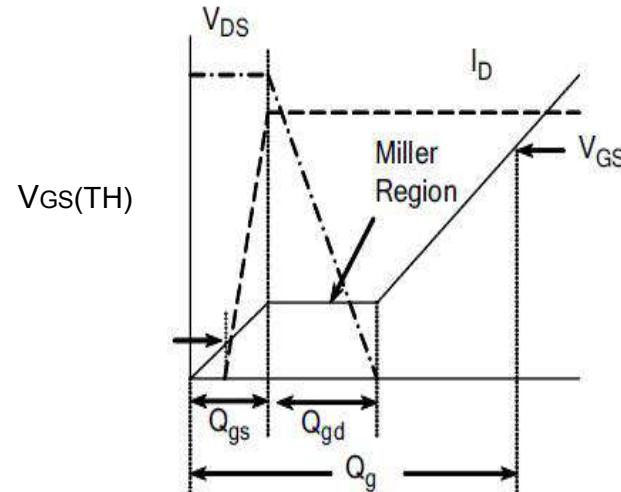


Figure12.
Gate Charge Waveform

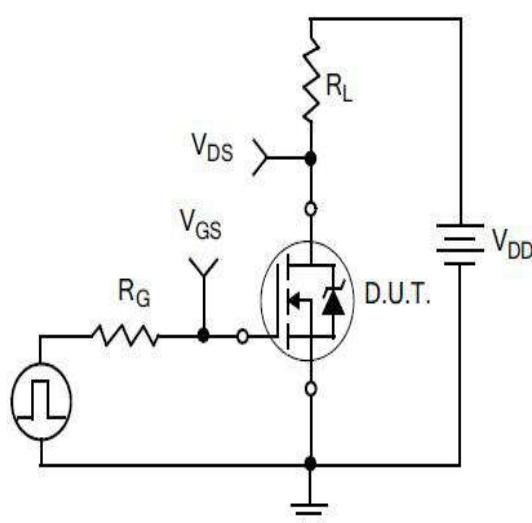


Figure13.
Resistive Switching Test Circuit

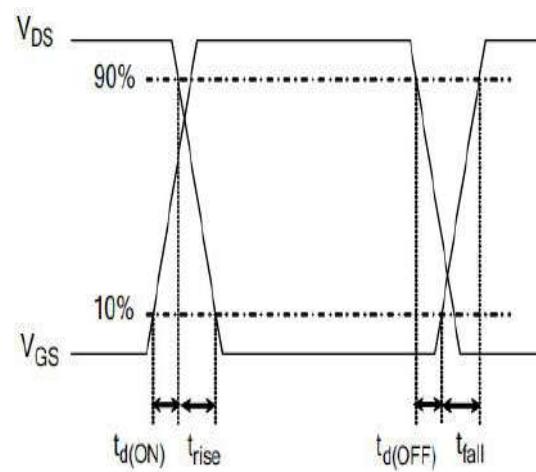


Figure14.
Resistive Switching Waveforms

Test Circuits and Waveforms

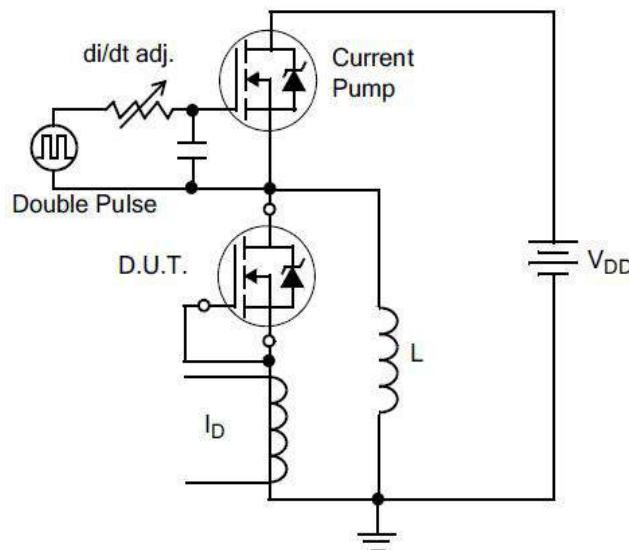


Figure15.Diode Reverse Recovery Test Circuit

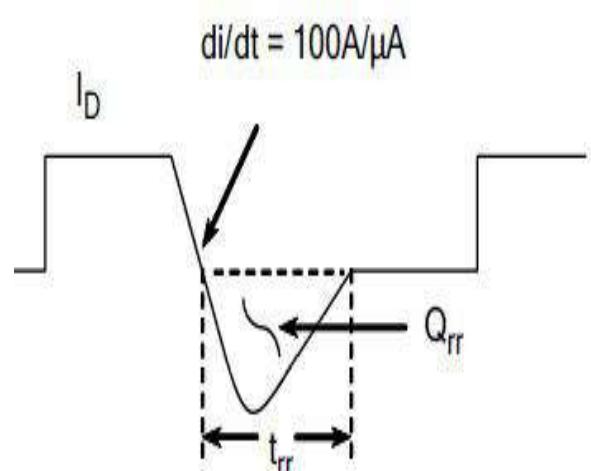


Figure16.Diode Reverse Recovery Waveform

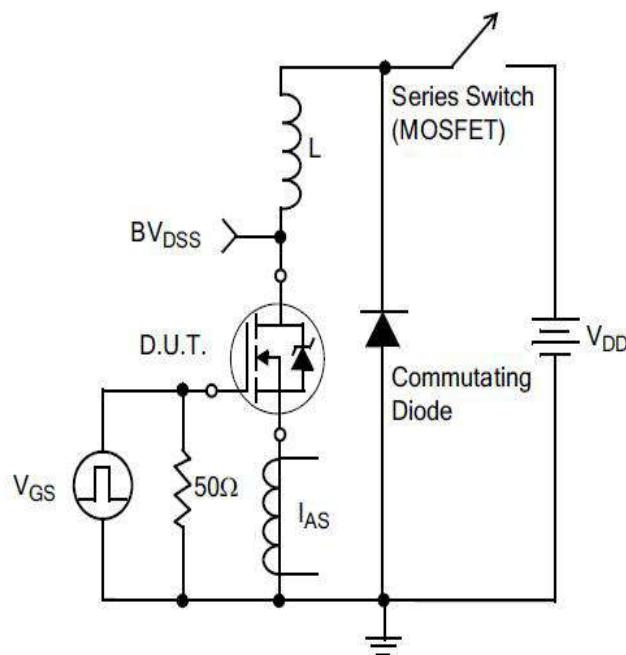
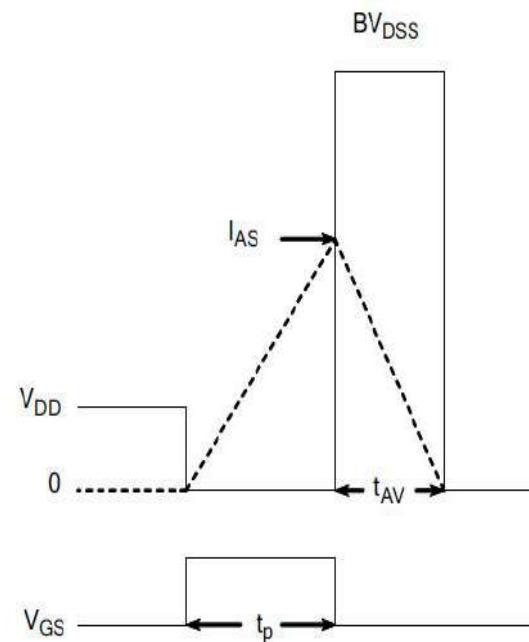


Figure17.Unclamped Inductive Switching Test Circuit



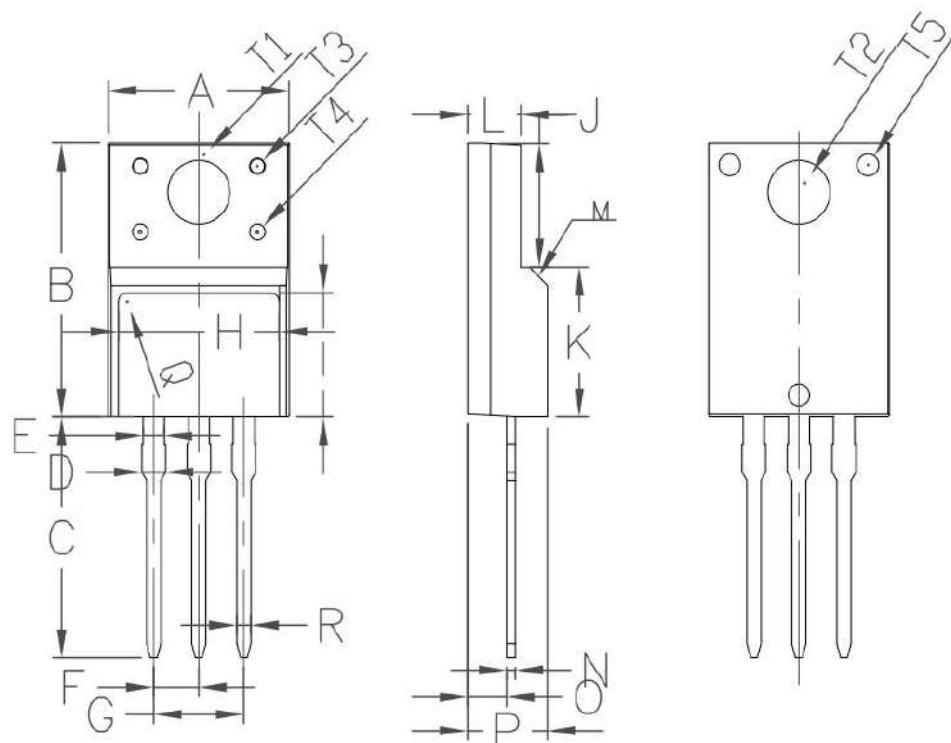
$$EAS = \frac{I_{AS}^2 L}{2}$$

Figure18.Unclamped Inductive Switching Waveforms

Package outline drawing

TO-220F

Unit: mm



Symbol	Min	Non	Max
A	9.96	10.16	10.36
B	15.67	15.87	16.07
C	13.14	13.34	13.54
D	1.20	1.30	1.40
E		1.20	
F		2.54	
G		5.08	
H	7.60	7.80	8.00
I	7.10	7.30	7.50
J	6.48	6.68	6.88
K	8.99	9.19	9.39
L	2.34	2.54	2.74
M		45°	
N	0.49	0.50	0.52
O	2.15	2.35	2.55
P	4.50	4.70	4.90
Q		0.50	
S	4°	4.5°	5°
T1		3.45	
T2		3.18	
T3		1.50	
T4		1.20	
T5		1.50	
R	0.77	0.8	0.83

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